

<b>Notice of References Cited</b>	Application/Control No. 10/722,606	Applicant(s)/Patent Under Reexamination LIN, CHIN-CHIH	
	Examiner Tan Le	Art Unit 3632	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
X	A	US-6,874,743	04-2005	Watanabe et al.	248/276.1
X	B	US-2004/0079858	04-2004	Rudolf, Alain	248/919
X	C	US-2004/0084578	05-2004	Cho et al.	248/125.1
X	D	US-2005/0092873	05-2005	Lin, Chin-Chih	248/125.9
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.